

6427525 N E C ELECTRONICS INC

81C 10361 DT-73-65

NEC

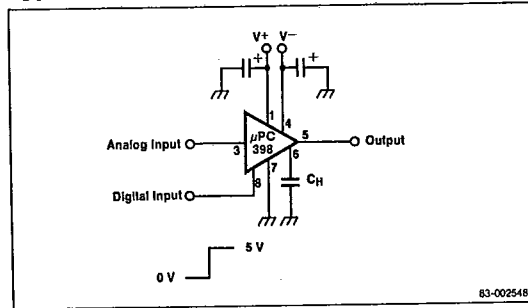
μPC398

Recommended Operating Conditions

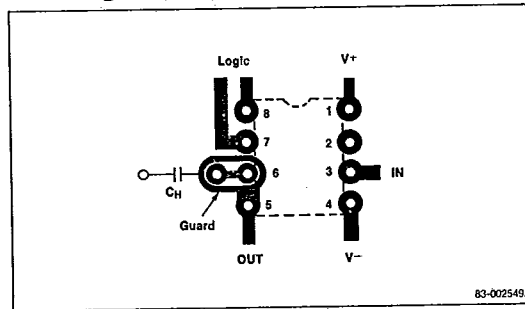
$T_A = 25^\circ\text{C}, V_{\pm} = \pm 15\text{V}$

Parameter	Symbol	Limits			Unit	Test Conditions
		Min.	Typ.	Max.		
Power Supply Voltage	V_{\pm}	± 5	± 15	± 16.5	V	
Analog Input Voltage	V_{IN}	-11.5		+11.5	V	
Sample Mode Logic Input Voltage	V_{SH}	2.7		5.25	V	$V_{REF} = 0$
Hold Mode Logic Input Voltage	V_{SH}	-15		0.5	V	$V_{REF} = 0$
Logic Input Voltage Slew Rate	SR	0.2			V/μs	
Hold Capacitor	C_H	0.001		0.1	μF	

Typical Connection



Guarding Technique (Bottom View)



Electrical Characteristics

$T_A = 25^\circ\text{C}, V_{\pm} = \pm 15\text{V}, -11.5\text{V} \leq V_{IN} \leq +11.5\text{V}, C_H = 0.01\ \mu\text{F}, R_L = 10\ \text{k}\Omega$

Parameter	Symbol	Limits			Unit	Test Conditions
		Min.	Typ.	Max.		
Input Offset Voltage	V_{io}			7.0	mV	
Input Bias Current	I_b			50	nA	
Input Impedance	R_{IN}		10^{10}		Ω	
Gain Error				0.01	%	
Feedthrough Attenuation Ratio		80			dB	$f = 1\ \text{kHz}$
Output Impedance	Z_o			4.0	Ω	
Hold Step Voltage	V_{HS}			2.5	mV	$V_O = 0$
Leakage Current into Hold Capacitor	I_{OLK}			200	μA	$V_{\pm} = \pm 5\text{V to } \pm 18\text{V}$
Acquisition Time	t_{aq}		4		μs	$\Delta V_O = 10\text{V}, 0.1\% \text{ Error}, C_H = 1000\ \text{pF}$
	t_{eq}		20		μs	$\Delta V_O = 10\text{V}, 0.1\% \text{ Error}, C_H = 0.01\ \text{pF}$
Hold Capacitor Charging Current	I_{CH}		5		mA	$V_{IN} - V_O = 2\text{V}$
Logic Input Current	I_{IN}			10	μA	
Logic Threshold	V_{TH}	0.8		2.4	V	
Supply Voltage Rejection Ratio	SVRR	80			dB	
Supply Current	I_{CC}			± 6.5	mA	$V_{\pm} = \pm 15\text{V to } \pm 18\text{V}$